はんだ上がり欠陥

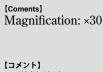
【原因、判断要点、发生工序】在 DFR 上夹杂着与线 宽同等或者稍大的圆形杂物,妨碍曝光所引起的(曝光~ET 工序)。

[Causes/processes involved/keys to judgment]

The defect is caused by a round foreign object staying on dry film of the same or somewhat larger size than the conductor width and blocking the exposure light. (Exposure and etching process)



[コメント] 顕微鏡倍率× 30 [注释] 显微镜倍率 × 30





[コメント] 顕微鏡倍率×50 [注释] 显微镜倍率×50 [Coments] Magnification:×50

1-1-1-7 **針状断線**/針状的开路 / Needle-shaped open

【特徴】断線部の先端が針状にとがっている断線

【特征】开路的前端像针那样尖锐。

[Characteristics] The tip of the broken conductor is like a needle point.

【原因・判断ポイント・発生工程】DFRとAWF間に介在した気泡がレンズ機能を果たす、或いは不透明で薄い帯状異物が、回路線を斜めに横切る、回路線の片側に薄く不透明な円弧状の異物がDFR上に介在し、回路焼付露光が遮ぎられて出来たもの(露光焼付~ET工程)

【原因、判断要点、发生工序】在 DFR 和 AWF 之间存在的气泡发挥透镜功能,或者不透明的薄片杂物斜跨线路,抑或在线路的单侧夹杂不透明的薄片圆弧状杂物,妨碍曝光而引起的(曝光~ET工序)。

[Causes/processes involved/keys to judgment]

The defect is caused by block the exposure light by a bubble present between dry film and a phototool acting as a lens, by an opaque thin foreign object strip diagonally crosses the conductors, or by an opaque thin arc-shaped foreign object stays on dry film. (Exposure and etching process)



顕微鏡倍率×30 [注釋] 显微镜倍率×30

Magnification: ×30



[コメント] 顕微鏡倍率×20 [注释] 显微镜倍率×20 [Coments] Magnification:×20